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#### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "[Embedded - Microcontrollers](#)"

##### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, EBI/EMI, I²C, MMC/SD, QSPI, SCI, SSIE, SPI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	52
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	192K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 18x14b; D/A 2x8b, 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LFQFP (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a17c3a01cfm-aa0">https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a17c3a01cfm-aa0</a>

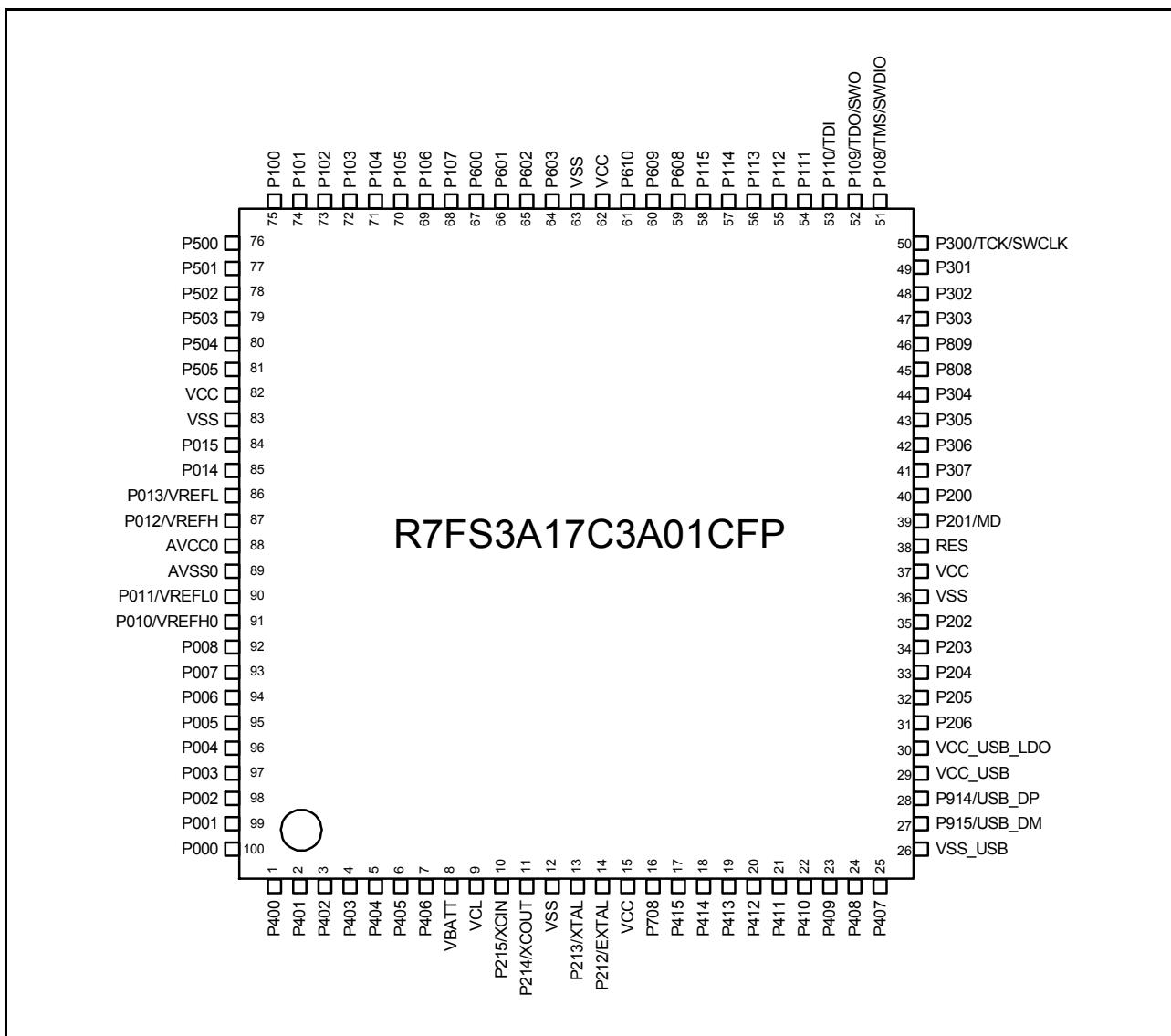


Figure 1.6 Pin assignment for 100-pin LQFP (top view)

## 2. Electrical Characteristics

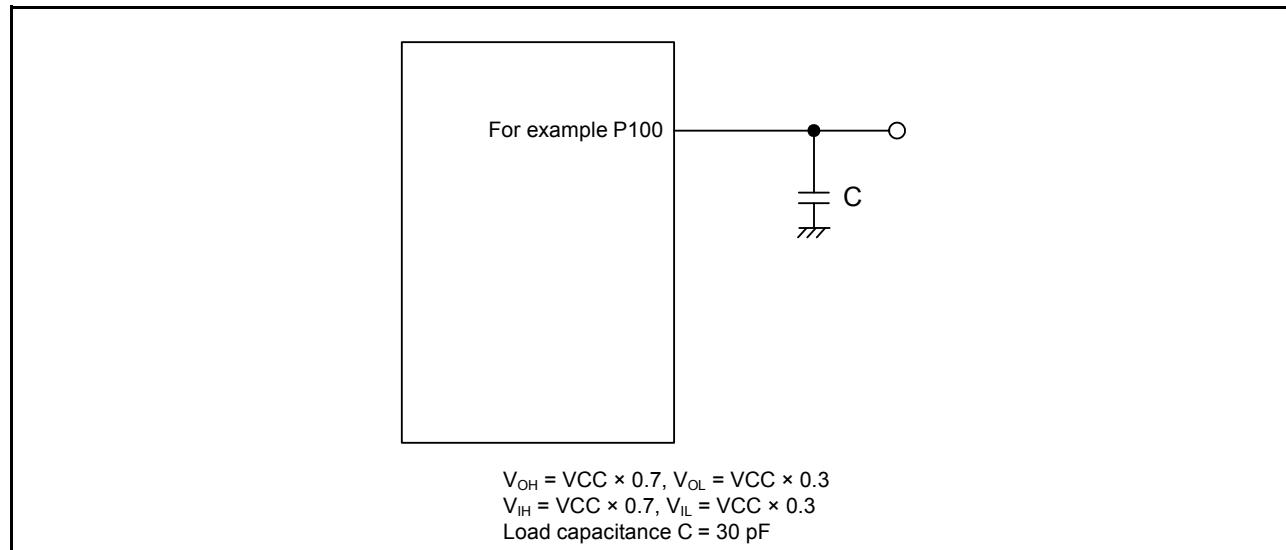
Unless otherwise specified, the electrical characteristics of the MCU are defined under the following conditions:

$VCC^*1 = AVCC0 = VCC\_USB^*2 = VCC\_USB\_LDO^*2 = 1.6$  to  $5.5$  V,  $VRERH = VREFH0 = 1.6$  to  $AVCC0$ ,  $VBATT = 1.6$  to  $3.6$  V,  $VSS = AVSS0 = VREFL = VREFL0 = VSS\_USB = 0$  V,  $Ta = T_{opr}$

Note 1. The typical condition is set to  $VCC = 3.3$ V.

Note 2. When USBFS is not used.

Figure 2.1 shows the timing conditions.



**Figure 2.1 Input or output timing measurement conditions**

The measurement conditions of timing specifications in each peripheral are recommended for the best peripheral operation. However, make sure to adjust driving abilities of each pin to meet your conditions.

Each function pin used for the same function must select the same drive ability. If the I/O drive ability of each function pin is mixed, the AC specification of each function is not guaranteed.

**Table 2.6 I/O  $I_{OH}$ ,  $I_{OL}$  (2 of 2)**

Conditions: VCC = AVCC0 = VCC\_USB = VCC\_USB\_LCO = 1.6 to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit
Permissible output current (Max value per pin)	Ports P212, P213	-	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
	Port P408	Low drive* <sup>1</sup>	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
		Middle drive for IIC Fast-mode* <sup>4</sup> VCC = 2.7 to 5.5 V	$I_{OH}$	-	-	-8.0	mA
			$I_{OL}$	-	-	8.0	mA
		Middle drive* <sup>2</sup> VCC = 3.0 to 5.5 V	$I_{OH}$	-	-	-20.0	mA
			$I_{OL}$	-	-	20.0	mA
	Port P409	Low drive* <sup>1</sup>	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
		Middle drive* <sup>2</sup> VCC = 2.7 to 3.0 V	$I_{OH}$	-	-	-8.0	mA
			$I_{OL}$	-	-	8.0	mA
		Middle drive* <sup>2</sup> VCC = 3.0 to 5.5 V	$I_{OH}$	-	-	-20.0	mA
			$I_{OL}$	-	-	20.0	mA
	Ports P100 to P115, P201 to P204, P300 to P315, P500 to P503, P600 to P606, P608 to P614, P800 to P809, P900 to P902 (total 67 pins)	Low drive* <sup>1</sup>	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
		Middle drive* <sup>2</sup>	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	8.0	mA
	Ports P914, P915	-	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
	Other output pin* <sup>3</sup>	Low drive* <sup>1</sup>	$I_{OH}$	-	-	-4.0	mA
			$I_{OL}$	-	-	4.0	mA
		Middle drive* <sup>2</sup>	$I_{OH}$	-	-	-8.0	mA
			$I_{OL}$	-	-	8.0	mA
Permissible output current (max value total pins)	Total of ports P000 to P015		$\Sigma I_{OH} \text{ (max)}$	-	-	-30	mA
			$\Sigma I_{OL} \text{ (max)}$	-	-	30	mA
	Ports P914, P915		$\Sigma I_{OH} \text{ (max)}$	-	-	-4.0	mA
			$\Sigma I_{OL} \text{ (min)}$	-	-	4.0	mA
	Total of all output pin* <sup>5</sup>		$\Sigma I_{OH} \text{ (max)}$	-	-	-60	mA
			$\Sigma I_{OL} \text{ (max)}$	-	-	60	mA

**Caution:** To protect the reliability of the MCU, the output current values should not exceed the values in this table. The average output current indicates the average value of current measured during 100  $\mu$ s.

- Note 1. This is the value when low driving ability is selected with the Port Drive Capability bit in PmnPFS register.
- Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.
- Note 3. Except for ports P200, P214, P215, which are input ports.
- Note 4. This is the value when middle driving ability for IIC Fast-mode is selected with the Port Drive Capability bit in PmnPFS register.
- Note 5. For details on the permissible output current used with CTSU, see [section 2.11, CTSU Characteristics](#).

## 2.2.4 I/O $V_{OH}$ , $V_{OL}$ , and Other Characteristics

**Table 2.7 I/O  $V_{OH}$ ,  $V_{OL}$  (1)**

Conditions: VCC = AVCC0 = VCC\_USB = VCC\_USB\_LCO = 4.0 to 5.5 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	IIC*1	$V_{OL}$	-	-	0.4	V	$I_{OL} = 3.0 \text{ mA}$
		$V_{OL}^{*2, *5}$	-	-	0.6		$I_{OL} = 6.0 \text{ mA}$
	Ports P408, P409*2, *3	$V_{OH}$	VCC – 1.0	-	-		$I_{OH} = -20 \text{ mA}$
		$V_{OL}$	-	-	1.0		$I_{OL} = 20 \text{ mA}$
	Ports P000 to P015	Low drive	$V_{OH}$	AVCC0 – 0.8	-		$I_{OH} = -2.0 \text{ mA}$
			$V_{OL}$	-	0.8		$I_{OL} = 2.0 \text{ mA}$
		Middle drive	$V_{OH}$	AVCC0 – 0.8	-		$I_{OH} = -4.0 \text{ mA}$
			$V_{OL}$	-	0.8		$I_{OL} = 4.0 \text{ mA}$
	Ports P914, P915	$V_{OH}$	VCC_USB – 0.8	-	-		$I_{OH} = -2.0 \text{ mA}$
		$V_{OL}$	-	-	0.8		$I_{OL} = 2.0 \text{ mA}$
	Other output pins*4	Low drive	$V_{OH}$	VCC – 0.8	-		$I_{OH} = -2.0 \text{ mA}$
			$V_{OL}$	-	0.8		$I_{OL} = 2.0 \text{ mA}$
		Middle drive*6	$V_{OH}$	VCC – 0.8	-		$I_{OH} = -4.0 \text{ mA}$
			$V_{OL}$	-	0.8		$I_{OL} = 4.0 \text{ mA}$

Note 1. P100, P101, P204, P205, P206, P400, P401, P407, P408, P511, P512 (total 11 pins).

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 3. Based on characterization data, not tested in production.

Note 4. Except for ports P200, P214, P215, which are input ports.

Note 5. This is the value when middle driving ability for IIC is selected with the Port Drive Capability bit in PmnPFS register for P408.

Note 6. Except for P212, P213.

**Table 2.8 I/O  $V_{OH}$ ,  $V_{OL}$  (2)**

Conditions: VCC = AVCC0 = VCC\_USB = VCC\_USB\_LCO = 2.7 to 4.0 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	IIC*1	$V_{OL}$	-	-	0.4	V	$I_{OL} = 3.0 \text{ mA}$
		$V_{OL}^{*2, *5}$	-	-	0.6		$I_{OL} = 6.0 \text{ mA}$
	Ports P408, P409*2, *3	$V_{OH}$	VCC – 1.0	-	-		$I_{OH} = -20 \text{ mA}$ VCC = 3.3 V
		$V_{OL}$	-	-	1.0		$I_{OL} = 20 \text{ mA}$ VCC = 3.3 V
	Ports P000 to P015	Low drive	$V_{OH}$	AVCC0 – 0.5	-		$I_{OH} = -1.0 \text{ mA}$
			$V_{OL}$	-	0.5		$I_{OL} = 1.0 \text{ mA}$
		Middle drive	$V_{OH}$	AVCC0 – 0.5	-		$I_{OH} = -2.0 \text{ mA}$
			$V_{OL}$	-	0.5		$I_{OL} = 2.0 \text{ mA}$
	Ports P914, P915	$V_{OH}$	VCC_USB – 0.5	-	-		$I_{OH} = -1.0 \text{ mA}$
		$V_{OL}$	-	-	0.5		$I_{OL} = 1.0 \text{ mA}$
	Other output pins*4	Low drive	$V_{OH}$	VCC – 0.5	-		$I_{OH} = -1.0 \text{ mA}$
			$V_{OL}$	-	0.5		$I_{OL} = 1.0 \text{ mA}$
		Middle drive*6	$V_{OH}$	VCC – 0.5	-		$I_{OH} = -2.0 \text{ mA}$
			$V_{OL}$	-	0.5		$I_{OL} = 2.0 \text{ mA}$

Note 1. P100, P101, P204, P205, P206, P400, P401, P407, P408, P511, P512 (total 11 pins).

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 3. Based on characterization data, not tested in production.

Note 4. Except for ports P200, P214, P215, which are input ports.

Note 5. This is the value when middle driving ability for IIC is selected with the Port Drive Capability bit in PmnPFS register for P408.

Note 6. Except for P212, P213.

**Table 2.9 I/O  $V_{OH}$ ,  $V_{OL}$  (3)**

Conditions: VCC = AVCC0 = VCC\_USB = VCC\_USB\_LCO = 1.6 to 2.7 V

Parameter			Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	Ports P000 to P015	Low drive	$V_{OH}$	AVCC0 – 0.3	-	-	V	$I_{OH} = -0.5 \text{ mA}$
			$V_{OL}$	-	-	0.3		$I_{OL} = 0.5 \text{ mA}$
		Middle drive	$V_{OH}$	AVCC0 – 0.3	-	-		$I_{OH} = -1.0 \text{ mA}$
			$V_{OL}$	-	-	0.3		$I_{OL} = 1.0 \text{ mA}$
	Ports P914, P915		$V_{OH}$	VCC_USB – 0.3	-	-		$I_{OH} = -0.5 \text{ mA}$
			$V_{OL}$	-	-	0.3		$I_{OL} = 0.5 \text{ mA}$
	Other output pins*1	Low drive	$V_{OH}$	VCC – 0.3	-	-		$I_{OH} = -0.5 \text{ mA}$
			$V_{OL}$	-	-	0.3		$I_{OL} = 0.5 \text{ mA}$
		Middle drive*2	$V_{OH}$	VCC – 0.3	-	-		$I_{OH} = -1.0 \text{ mA}$
			$V_{OL}$	-	-	0.3		$I_{OL} = 1.0 \text{ mA}$

Note 1. Except for ports P200, P214, P215, which are input ports.

Note 2. Except for P212, P213.

**Table 2.10 I/O other characteristics**

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Input leakage current	RES, P200, P214, P215	$ I_{in} $	-	-	1.0	$\mu\text{A}$	$V_{in} = 0 \text{ V}$ $V_{in} = \text{VCC}$
Three-state leakage current (off state)	5V-tolerant ports	$ I_{TSI} $	-	-	1.0	$\mu\text{A}$	$V_{in} = 0 \text{ V}$ $V_{in} = 5.8 \text{ V}$
	Other ports (except for ports P200, P214, P215 and 5 V tolerant)		-	-	1.0		$V_{in} = 0 \text{ V}$ $V_{in} = \text{VCC}$
Input pull-up resistor	All ports (except for ports P200, P214, P215, P914, P915)	$R_U$	10	20	50	$\text{k}\Omega$	$V_{in} = 0 \text{ V}$
Input capacitance	P914, P915, P100 to P103, P111, P112, P200	$C_{in}$	-	-	30	$\text{pF}$	$V_{in} = 0 \text{ V}$ $f = 1 \text{ MHz}$ $T_a = 25^\circ\text{C}$
	Other input pins		-	-	15		

## 2.2.9 Operating and Standby Current

**Table 2.11 Operating and standby current (1) (1 of 2)**

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter					Symbol	Typ <sup>*10</sup>	Max	Unit	Test conditions
Supply current <sup>*1</sup>	High-speed mode <sup>*2</sup>	Normal mode	All peripheral clocks disabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 48 MHz	I <sub>CC</sub>	9.3	-	mA	*7
				ICLK = 32 MHz		6.7	-		
				ICLK = 16 MHz		4.1	-		
				ICLK = 8 MHz		2.7	-		
			All peripheral clocks disabled, CoreMark code executing from flash <sup>*5</sup>	ICLK = 48 MHz	I <sub>CC</sub>	18.8	-	mA	*9
				ICLK = 32 MHz		13.1	-		
				ICLK = 16 MHz		7.5	-		
				ICLK = 8 MHz		4.7	-		
		All peripheral clocks enabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 48 MHz	I <sub>CC</sub>	22.4	-	mA	*8	
			ICLK = 32 MHz	I <sub>CC</sub>	16.9	-			
			ICLK = 16 MHz	I <sub>CC</sub>	9.4	-			
			ICLK = 8 MHz	I <sub>CC</sub>	5.5	-			
		Sleep mode	All peripheral clocks enabled, code executing from SRAM <sup>*5</sup>	ICLK = 48 MHz	I <sub>CC</sub>	-	62.0	mA	*9
			All peripheral clocks disabled <sup>*5</sup>	ICLK = 48 MHz		4.0	-		
				ICLK = 32 MHz		3.1	-		
				ICLK = 16 MHz		2.3	-		
				ICLK = 8 MHz		1.8	-		
			All peripheral clocks enabled <sup>*5</sup>	ICLK = 48 MHz		16.8	-		*9
				ICLK = 32 MHz		13.0	-		
				ICLK = 16 MHz		7.4	-		
				ICLK = 8 MHz		4.5	-		
			Increase during BGO operation <sup>*6</sup>			2.5	-		-
	Middle-speed mode <sup>*2</sup>	Normal mode	All peripheral clocks disabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 12 MHz	I <sub>CC</sub>	2.8	-	mA	*7
				ICLK = 8 MHz		2.3	-		
				ICLK = 1 MHz		1.1	-		
			All peripheral clocks disabled, CoreMark code executing from flash <sup>*5</sup>	ICLK = 12 MHz		5.4	-		*8
				ICLK = 8 MHz		4.2	-		
				ICLK = 1 MHz		1.4	-		
			All peripheral clocks enabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 12 MHz		6.9	-		
				ICLK = 8 MHz		5.1	-		
				ICLK = 1 MHz		1.7	-		
		Sleep mode	All peripheral clocks enabled, code executing from SRAM <sup>*5</sup>	ICLK = 12 MHz		-	25.0		*7
			All peripheral clocks disabled <sup>*5</sup>	ICLK = 12 MHz		1.5	-		
				ICLK = 8 MHz		1.4	-		
				ICLK = 1 MHz		1.0	-		
			All peripheral clocks enabled <sup>*5</sup>	ICLK = 12 MHz		5.4	-		*8
				ICLK = 8 MHz		4.1	-		
				ICLK = 1 MHz		1.6	-		
			Increase during BGO operation <sup>*6</sup>			2.5	-		-

**Table 2.11 Operating and standby current (1) (2 of 2)**

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter					Symbol	Typ <sup>*10</sup>	Max	Unit	Test conditions
Supply current <sup>*1</sup>	Low-speed mode <sup>*3</sup>	Normal mode	All peripheral clocks disabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 1 MHz	I <sub>CC</sub>	0.4	-	mA	*7
			All peripheral clocks disabled, CoreMark code executing from flash <sup>*5</sup>	ICLK = 1 MHz		0.6	-		
			All peripheral clocks enabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 1 MHz		1.1	-		*8
			All peripheral clocks enabled, code executing from SRAM <sup>*5</sup>	ICLK = 1 MHz		-	2.6		
		Sleep mode	All peripheral clocks disabled <sup>*5</sup>	ICLK = 1 MHz		0.3	-		*7
			All peripheral clocks enabled <sup>*5</sup>	ICLK = 1 MHz		1.0	-		*8
	Low-voltage mode <sup>*3</sup>	Normal mode	All peripheral clocks disabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 4 MHz	I <sub>CC</sub>	2.2	-	mA	*7
			All peripheral clocks disabled, CoreMark code executing from flash <sup>*5</sup>	ICLK = 4 MHz		3.3	-		
			All peripheral clocks enabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 4 MHz		3.7	-		*8
			All peripheral clocks enabled, code executing from SRAM <sup>*5</sup>	ICLK = 4 MHz		-	10.0		
		Sleep mode	All peripheral clocks disabled <sup>*5</sup>	ICLK = 4 MHz		1.7	-		*7
			All peripheral clocks enabled <sup>*5</sup>	ICLK = 4 MHz		3.2	-		*8
	Subosc-speed mode <sup>*4</sup>	Normal mode	All peripheral clocks disabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 32.768 kHz	I <sub>CC</sub>	10.0	-	μA	*8
			All peripheral clocks enabled, while (1) code executing from flash <sup>*5</sup>	ICLK = 32.768 kHz		17.9	-		
			All peripheral clocks enabled, code executing from SRAM <sup>*5</sup>	ICLK = 32.768 kHz		-	154.0		
		Sleep mode	All peripheral clocks disabled <sup>*5</sup>	ICLK = 32.768 kHz		6.3	-		
			All peripheral clocks enabled <sup>*5</sup>	ICLK = 32.768 kHz		14.0	-		

Note 1. Supply current values do not include output charge/discharge current from all pins. The values apply when internal pull-up MOSs are in the off state.

Note 2. The clock source is HOCO.

Note 3. The clock source is MOCO.

Note 4. The clock source is the sub-clock oscillator.

Note 5. This does not include BGO operation.

Note 6. This is the increase for programming or erasure of the flash memory for data storage during program execution.

Note 7. FCLK, BCLK, PCLKA, PCLKB, PCLKC, and PCLKD are set to divided by 64.

Note 8. FCLK, BCLK, PCLKA, PCLKB, PCLKC, and PCLKD are the same frequency as that of ICLK.

Note 9. FCLK, BCLK, and PCLKB are set to divided by 2 and PCLKA, PCLKC, and PCLKD are the same frequency as that of ICLK.

Note 10. VCC = 3.3 V.

## 2.3 AC Characteristics

### 2.3.1 Frequency

**Table 2.17 Operation frequency value in high-speed operating mode**

Conditions: VCC = AVCC0 = 2.4 to 5.5 V

Parameter		Symbol	Min	Typ	Max <sup>*5</sup>	Unit	
Operation frequency	System clock (ICLK) <sup>*4</sup>	f	0.032768	-	48	MHz	
			0.032768	-	16		
	FlashIF clock (FCLK) <sup>*1, *2, *4</sup>		0.032768	-	32		
			0.032768	-	16		
	Peripheral module clock (PCLKA) <sup>*4</sup>		-	-	48		
			-	-	16		
	Peripheral module clock (PCLKB) <sup>*4</sup>		-	-	32		
			-	-	16		
	Peripheral module clock (PCLKC) <sup>*3, *4</sup>		-	-	64		
			-	-	16		
	Peripheral module clock (PCLKD) <sup>*4</sup>		-	-	64		
			-	-	16		
	External bus clock (BCLK) <sup>*4</sup>		-	-	24		
			-	-	16		
	EBCLK pin output		-	-	12		
			-	-	8		

- Note 1. The lower-limit frequency of FCLK is 1 MHz while programming or erasing the flash memory. When using FCLK for programming or erasing the flash memory at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.
- Note 2. The frequency accuracy of FCLK must be  $\pm 3.5\%$  while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.
- Note 3. The lower-limit frequency of PCLKC is 4 MHz at 2.4 V or above and 1 MHz at below 2.4 V when the 14-bit A/D converter is in use.
- Note 4. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.
- Note 5. The maximum value of operation frequency does not include the internal oscillator errors. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

Note 4. The maximum value of operation frequency does not include the internal oscillator errors. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

**Table 2.20 Operation frequency value in Low-voltage mode**

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter			Symbol	Min	Typ	Max <sup>*5</sup>	Unit
Operation frequency	System clock (ICLK) <sup>*4</sup>	1.6 to 5.5 V	f	0.032768	-	4	MHz
	FlashIF clock (FCLK) <sup>*1, *2, *4</sup>	1.6 to 5.5 V		0.032768	-	4	
	Peripheral module clock (PCLKA) <sup>*4</sup>	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKB) <sup>*4</sup>	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKC) <sup>*3, *4</sup>	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKD) <sup>*4</sup>	1.6 to 5.5 V		-	-	4	
	External bus clock (BCLK) <sup>*4</sup>	1.6 to 5.5 V		-	-	4	
	EBCLK pin output	1.8 to 5.5 V		-	-	4	
		1.6 to 1.8 V		-	-	2	

Note 1. The lower-limit frequency of FCLK is 1 MHz while programming or erasing the flash memory. When using FCLK for programming or erasing the flash memory at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.

Note 2. The frequency accuracy of FCLK must be  $\pm 3.5\%$  while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.

Note 3. The lower-limit frequency of PCLKC is 4 MHz at 2.4 V or above and 1 MHz at below 2.4 V when the 14-bit A/D converter is in use.

Note 4. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

Note 5. The maximum value of operation frequency does not include errors of the internal oscillator. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

**Table 2.21 Operation frequency value in Subosc-speed mode**

Conditions: VCC = AVCC0 = 1.8 to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit
Operation frequency	System clock (ICLK) <sup>*3</sup>	1.8 to 5.5 V	f	27.8528	32.768	37.6832	kHz
	FlashIF clock (FCLK) <sup>*1, *3</sup>	1.8 to 5.5 V		27.8528	32.768	37.6832	
	Peripheral module clock (PCLKA) <sup>*3</sup>	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKB) <sup>*3</sup>	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKC) <sup>*2, *3</sup>	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKD) <sup>*3</sup>	1.8 to 5.5 V		-	-	37.6832	
	External bus clock (BCLK) <sup>*3</sup>	1.8 to 5.5 V		-	-	37.6832	
	EBCLK pin output	1.8 to 5.5 V		-	-	37.6832	

Note 1. Programming and erasing the flash memory are not possible.

Note 2. The 14-bit A/D converter cannot be used.

Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

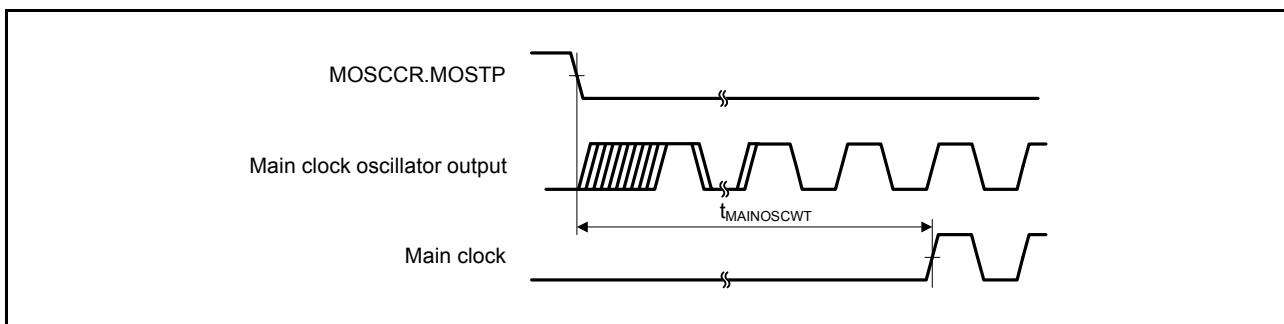


Figure 2.30 Main clock oscillation start timing

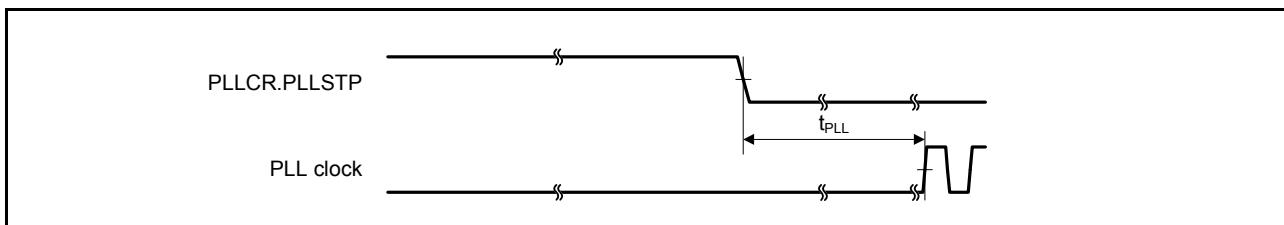


Figure 2.31 PLL clock oscillation start timing (PLL is operated after main clock oscillation has settled)

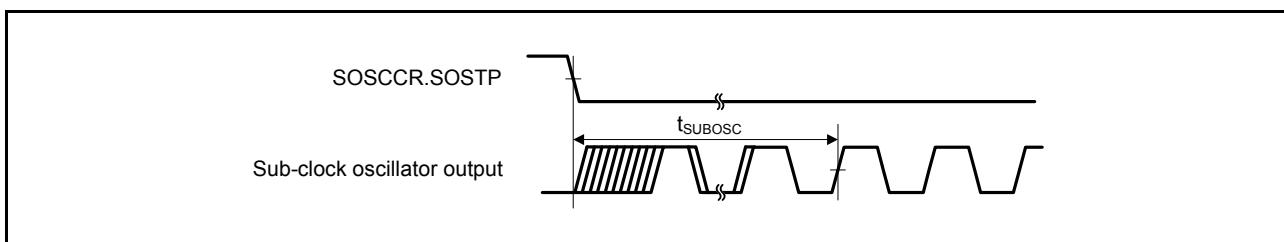


Figure 2.32 Sub-clock oscillation start timing

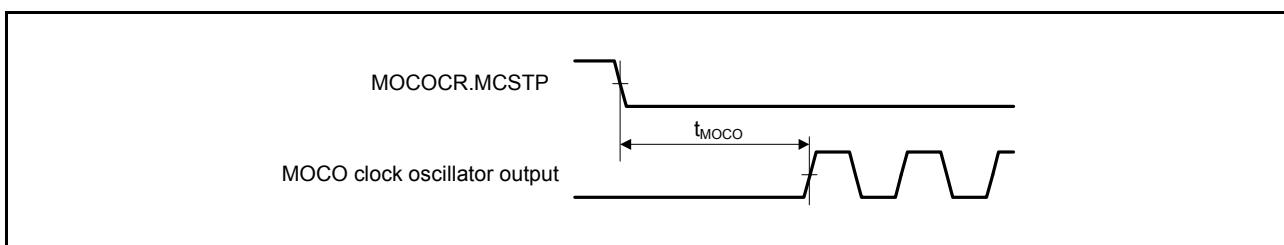


Figure 2.33 MOCO clock oscillation start timing

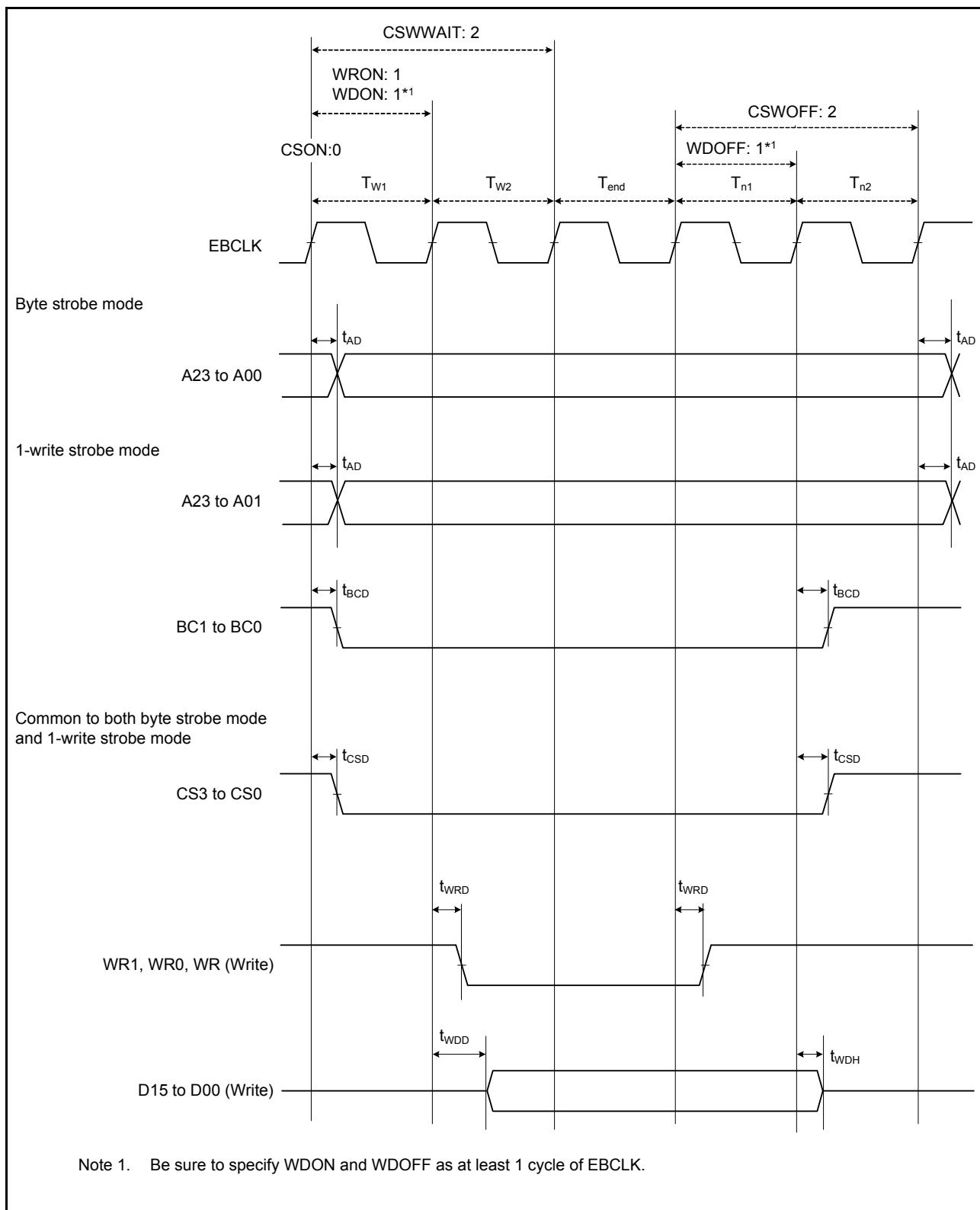


Figure 2.43 External bus timing/normal write cycle (bus clock synchronized)

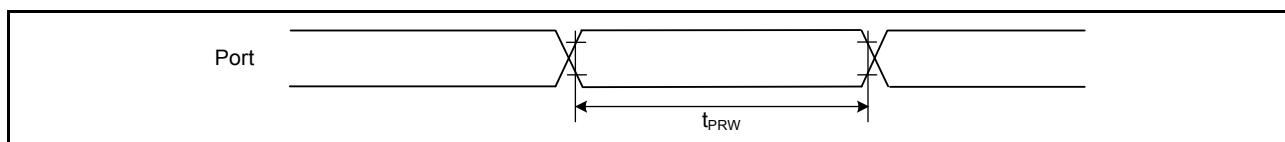
### 2.3.7 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 Trigger Timing

**Table 2.35 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 trigger timing**

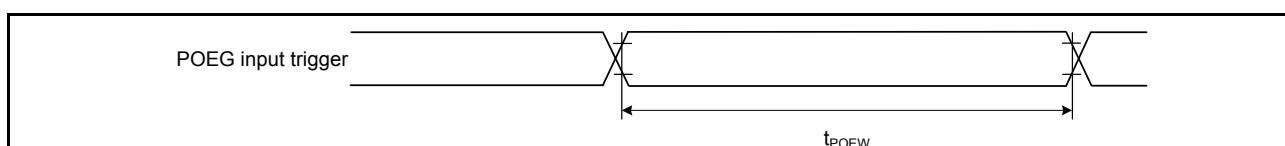
Parameter		Symbol	Min	Max	Unit	Test conditions
I/O ports	Input data pulse width	$t_{PRW}$	1.5	-	$t_{Pcyc}$	<a href="#">Figure 2.47</a>
	Input/output data cycle (P002, P003, P004, P007)	$t_{POcyc}$	10	-	us	
POEG	POEG input trigger pulse width	$t_{POEW}$	3	-	$t_{Pcyc}$	<a href="#">Figure 2.48</a>
GPT	Input capture pulse width	$t_{GTICW}$	1.5	-	$t_{PDcyc}$	<a href="#">Figure 2.49</a>
			2.5	-		
AGT	AGTIO, AGTEE input cycle	$t_{ACYC}^{*1}$	250	-	ns	<a href="#">Figure 2.50</a>
			500	-	ns	
			1000	-	ns	
			2000	-	ns	
	AGTIO, AGTEE input high level width, low-level width	$t_{ACKWH}, t_{ACKWL}$	100	-	ns	
			200	-	ns	
			400	-	ns	
			800	-	ns	
	AGTIO, AGTO, AGTOA, AGTOB output cycle	$t_{ACYC2}$	62.5	-	ns	<a href="#">Figure 2.50</a>
			125	-	ns	
			250	-	ns	
			500	-	ns	
ADC14	14-bit A/D converter trigger input pulse width	$t_{TRGW}$	1.5	-	$t_{Pcyc}$	<a href="#">Figure 2.51</a>
KINT	KRn ( $n = 00$ to $07$ ) pulse width	$t_{KR}$	250	-	ns	<a href="#">Figure 2.52</a>

Note 1. Constraints on AGTIO input:  $t_{Pcyc} \times 2 < t_{ACYC}$

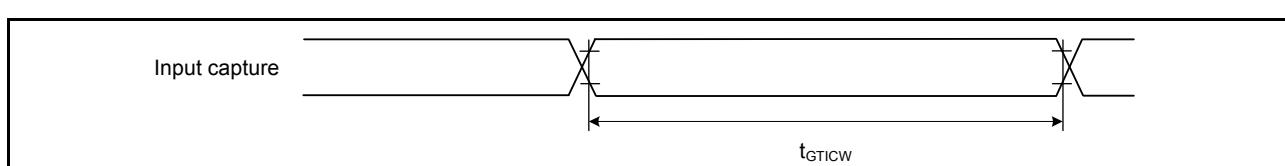
Note:  $t_{Pcyc}$ : PCLKB cycle,  $t_{PDcyc}$ : PCLKD cycle



**Figure 2.47 I/O ports input timing**



**Figure 2.48 POEG input trigger timing**



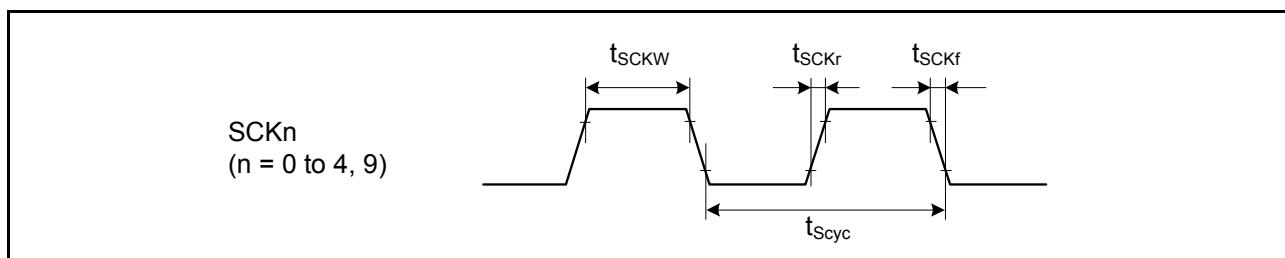
**Figure 2.49 GPT input capture timing**

### 2.3.9 SCI Timing

**Table 2.37 SCI timing (1)**

Parameter			Symbol	Min	Max	Unit*1	Test conditions	
SCI	Input clock cycle	Asynchronous	$t_{Scyc}$	4	-	$t_{Pcyc}$	Figure 2.53	
		Clock synchronous		6	-			
	Input clock pulse width			$t_{SCKW}$	0.4	0.6	$t_{Scyc}$	
	Input clock rise time			$t_{SCKr}$	-	20	ns	
	Input clock fall time			$t_{SCKf}$	-	20	ns	
	Output clock cycle	Asynchronous	$t_{Scyc}$	6	-	$t_{Pcyc}$		
		Clock synchronous		4	-			
	Output clock pulse width			$t_{SCKW}$	0.4	0.6	$t_{Scyc}$	
	Output clock rise time	1.8 V or above	$t_{SCKr}$	-	20	ns		
		1.6 V or above		-	30			
	Output clock fall time	1.8 V or above	$t_{SCKf}$	-	20	ns		
		1.6 V or above		-	30			
	Transmit data delay (master)	1.8 V or above	$t_{TXD}$	-	40	ns	Figure 2.54	
		1.6 V or above		-	45			
	Transmit data delay (slave)	2.7 V or above		-	55	ns		
		2.4 V or above		-	60			
		1.8 V or above		-	100			
		1.6 V or above		-	125			
		2.7 V or above		45	-	ns		
		2.4 V or above		55	-			
		1.8 V or above		90	-			
		1.6 V or above		110	-			
	Receive data setup time (slave)	2.7 V or above		40	-	ns		
		1.6 V or above		45	-			
	Receive data hold time (master)	Clock synchronous	$t_{RXH}$	5	-	ns		
	Receive data hold time (slave)	Clock synchronous	$t_{RXH}$	40	-	ns		

Note 1.  $t_{Pcyc}$ : PCLKA cycle.



**Figure 2.53 SCK clock input timing**

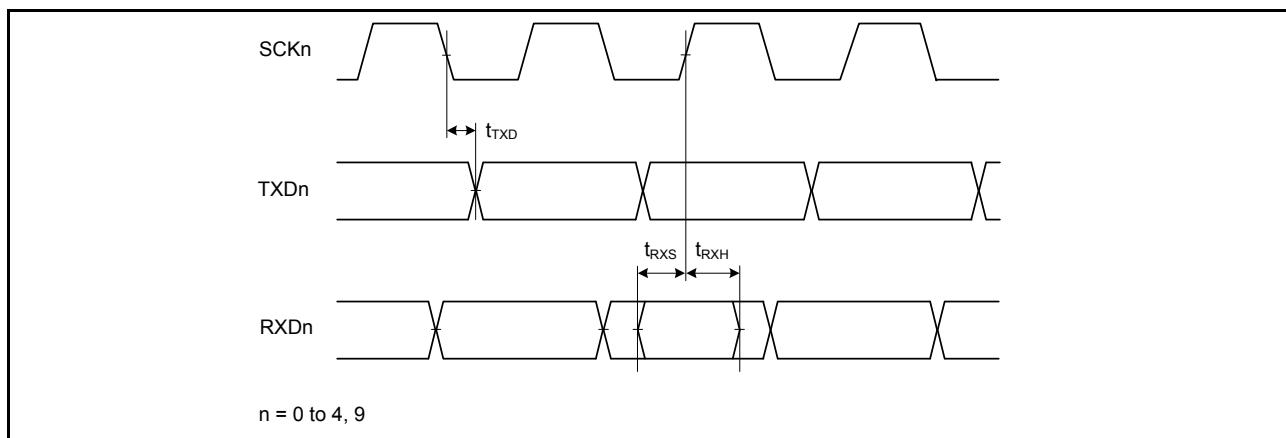


Figure 2.54 SCI input/output timing in clock synchronous mode

Table 2.38 SCI timing (2) (1 of 2)

Parameter			Symbol	Min	Max	Unit	Test conditions	
Simple SPI	SCK clock cycle output (master)		$t_{SPcyc}$	4	65536	$t_{SPcyc}$	Figure 2.55	
	SCK clock cycle input (slave)			6	65536			
	SCK clock high pulse width			$t_{SPCKWH}$	0.4	0.6		
	SCK clock low pulse width			$t_{SPCKWL}$	0.4	0.6		
	SCK clock rise and fall time	1.8 V or above	$t_{SPCKr}, t_{SPCKf}$	-	20	ns		
		1.6 V or above		-	30			
	Data input setup time	Master	$t_{SU}$	2.7 V or above	45	-	Figure 2.56 to Figure 2.59	
				2.4 V or above	55	-		
				1.8 V or above	80	-		
				1.6 V or above	110	-		
		Slave		2.7 V or above	40	-		
				1.6 V or above	45	-		
	Data input hold time	Master	$t_H$	33.3	-	ns		
		Slave		40	-			
	SS input setup time			$t_{LEAD}$	1	-	$t_{SPcyc}$	
	SS input hold time			$t_{LAG}$	1	-	$t_{SPcyc}$	
	Data output delay	Master	$t_{OD}$	1.8 V or above	-	40	ns	
				1.6 V or above	-	50		
		Slave		2.4 V or above	-	65		
				1.8 V or above	-	100		
				1.6 V or above	-	125		
	Data output hold time	Master		2.7 V or above	-10	-		
				2.4 V or above	-20	-		
				1.8 V or above	-30	-		
				1.6 V or above	-40	-		
		Slave		-10	-	-		
	Data rise and fall time	Master	$t_{Dr}, t_{Df}$	1.8 V or above	-	20	ns	
				1.6 V or above	-	30		
		Slave		1.8 V or above	-	20		
				1.6 V or above	-	30		

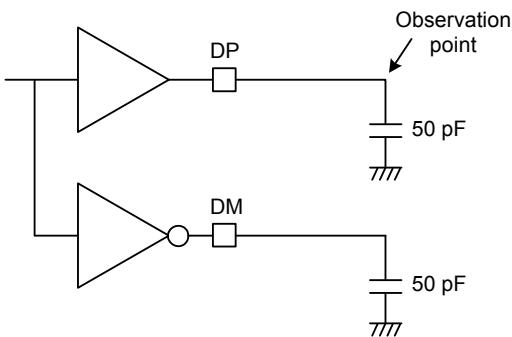


Figure 2.78 Test circuit for Full-Speed (FS) connection

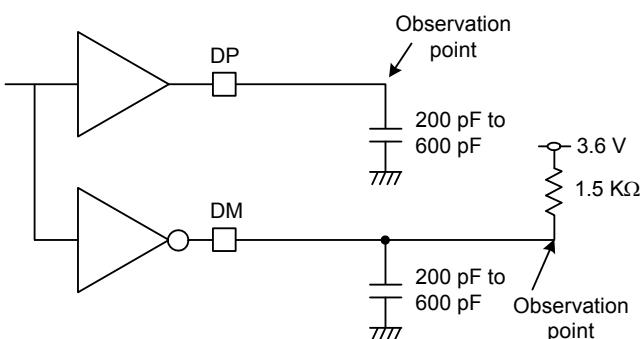


Figure 2.79 Test circuit for Low-Speed (LS) connection

#### 2.4.2 USB External Supply

Table 2.47 USB regulator

Parameter		Min	Typ	Max	Unit	Test conditions
VCC_USB supply current	VCC_USB_LDO $\geq 3.8V$	-	-	50	mA	-
	VCC_USB_LDO $\geq 4.5V$	-	-	100	mA	-
VCC_USB supply voltage	3.0	-	-	3.6	V	-

**Table 2.49 A/D conversion characteristics (2) in high-speed A/D conversion mode (2 of 2)**

Conditions: VCC = AVCC0 = 2.7 to 5.5 V, VREFH0 = 2.7 to 5.5 V

Reference voltage range applied to the VREFH0 and VREFL0.

Parameter	Min	Typ	Max	Unit	Test conditions	
14-bit mode						
Resolution	-	-	14	Bit	-	
Conversion time <sup>*1</sup> (Operation at PCLKC = 48 MHz)	1.06	-	-	μs	High-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 0Dh	
	1.63	-	-	μs	Normal-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 28h	
Offset error		-	±2.0	±18	LSB	High-precision channel
				±24.0	LSB	Other than above
Full-scale error		-	±3.0	±18	LSB	High-precision channel
				±24.0	LSB	Other than above
Quantization error		-	±0.5	-	LSB	-
Absolute accuracy		-	±5.0	±20	LSB	High-precision channel
				±32.0	LSB	Other than above
DNL differential nonlinearity error		-	±4.0	-	LSB	-
INL integral nonlinearity error		-	±4.0	±12.0	LSB	-

Note: The characteristics apply when no pin functions other than 14-bit A/D converter input are used. Absolute accuracy does not include quantization errors. Offset error, full-scale error, DNL differential nonlinearity error, and INL integral nonlinearity error do not include quantization errors.

Note 1. The conversion time is the sum of the sampling time and the comparison time. The number of sampling states is indicated for the test conditions.

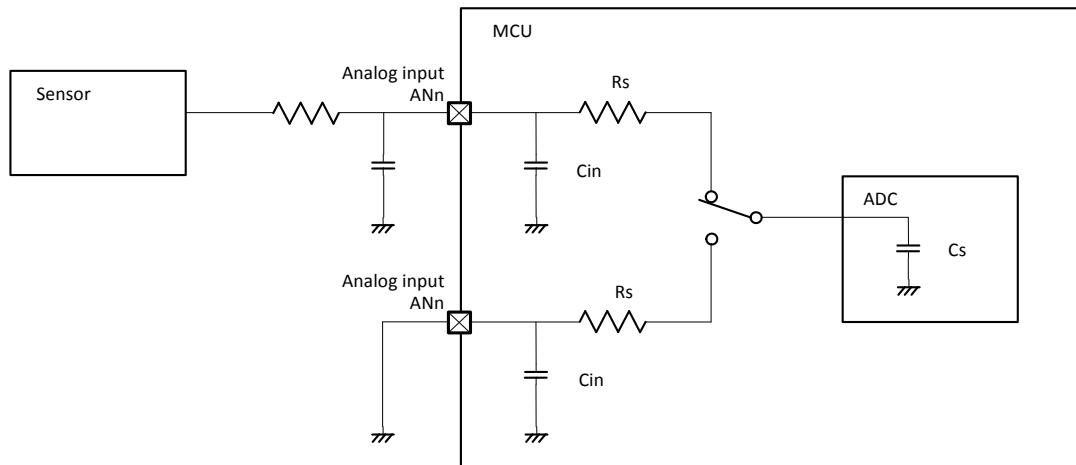
Note 2. Except for I/O input capacitance (Cin), see section 2.2.4, I/O V<sub>OH</sub>, V<sub>OL</sub>, and Other Characteristics.

**Table 2.50 A/D conversion characteristics (3) in high-speed A/D conversion mode (1 of 2)**

Conditions: VCC = AVCC0 = 2.4 to 5.5 V, VREFH0 = 2.4 to 5.5 V

Reference voltage range applied to the VREFH0 and VREFL0.

Parameter	Min	Typ	Max	Unit	Test conditions		
Frequency							
Frequency	1	-	32	MHz	-		
Analog input capacitance <sup>*2</sup>	Cs	-	8 (reference data)	pF	High-precision channel		
		-	9 (reference data)	pF	Normal-precision channel		
Analog input resistance		Rs	-	kΩ	High-precision channel		
		-	2.5 (reference data)	kΩ	Normal-precision channel		
Analog input voltage range	Ain	0	-	VREFH0	V		
12-bit mode							
Resolution	-	-	12	Bit	-		
Conversion time <sup>*1</sup> (Operation at PCLKC = 32 MHz)	Permissible signal source impedance Max. = 1.3 kΩ	1.41	-	μs	High-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 0Dh		
		2.25	-	μs	Normal-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 28h		
Offset error		-	±0.5	±4.5	LSB	High-precision channel	
				±6.0	LSB	Other than above	
Full-scale error		-	±0.75	±4.5	LSB	High-precision channel	
				±6.0	LSB	Other than above	
Quantization error		-	±0.5	-	LSB	-	
Absolute accuracy		-	±1.25	±5.0	LSB	High-precision channel	
				±8.0	LSB	Other than above	

**Figure 2.81** Equivalent circuit for analog input**Table 2.55** 14-bit A/D converter channel classification

Classification	Channel	Conditions	Remarks
High-precision channel	AN000 to AN015	AVCC0 = 1.6 to 5.5 V	Pins AN000 to AN015 cannot be used as general I/O, IRQ2, IRQ3 inputs, and TS transmission, when the A/D converter is in use
Normal-precision channel	AN016 to AN027		
Internal reference voltage input channel	Internal reference voltage	AVCC0 = 2.0 to 5.5 V	-
Temperature sensor input channel	Temperature sensor output	AVCC0 = 2.0 to 5.5 V	-

**Table 2.56** A/D internal reference voltage characteristicsConditions: VCC = AVCC0 = VREFH0 = 2.0 to 5.5 V<sup>\*1</sup>

Parameter	Min	Typ	Max	Unit	Test conditions
Internal reference voltage input channel <sup>*2</sup>	1.36	1.43	1.50	V	-
Frequency <sup>*3</sup>	1	-	2	MHz	-
Sampling time <sup>*4</sup>	5.0	-	-	μs	-

Note 1. The internal reference voltage cannot be selected for input channels when AVCC0 &lt; 2.0 V.

Note 2. The 14-bit A/D internal reference voltage indicates the voltage when the internal reference voltage is input to the 14-bit A/D converter.

Note 3. This is a parameter for ADC14 when the internal reference voltage is used as the high-potential reference voltage.

Note 4. This is a parameter for ADC14 when the internal reference voltage is selected for an analog input channel in ADC14.

## 2.7 TSN Characteristics

**Table 2.60 TSN characteristics**

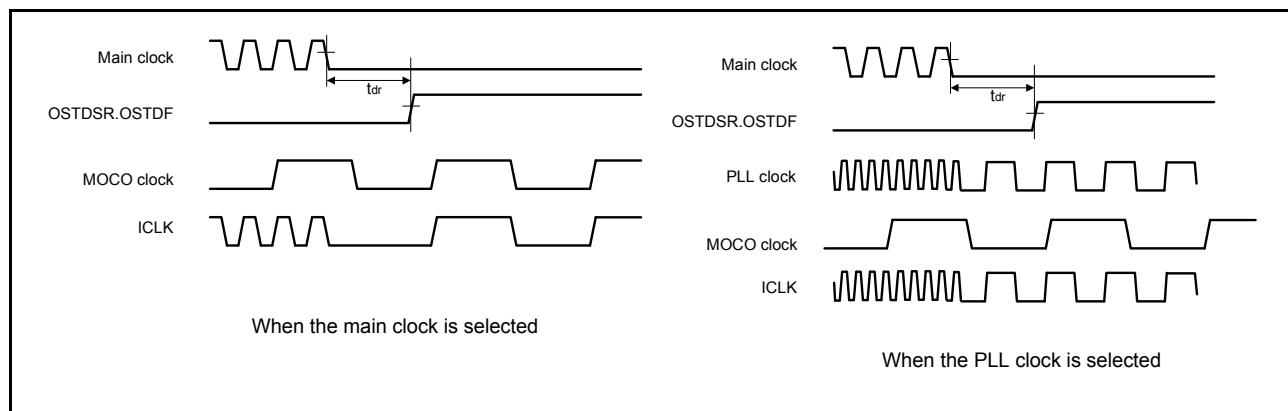
Conditions: VCC = AVCC0 = 2.0 to 5.5 V

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Relative accuracy	-	-	$\pm 1.5$	-	°C	2.4 V or above
	-	-	$\pm 2.0$	-	°C	Below 2.4 V
Temperature slope	-	-	-3.65	-	mV/°C	-
Output voltage (at 25°C)	-	-	1.05	-	V	VCC = 3.3 V
Temperature sensor start time	t <sub>START</sub>	-	-	5	μs	-
Sampling time	-	5	-	-	μs	-

## 2.8 OSC Stop Detect Characteristics

**Table 2.61 Oscillation stop detection circuit characteristics**

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Detection time	t <sub>dr</sub>	-	-	1	ms	<a href="#">Figure 2.84</a>



**Figure 2.84 Oscillation stop detection timing**

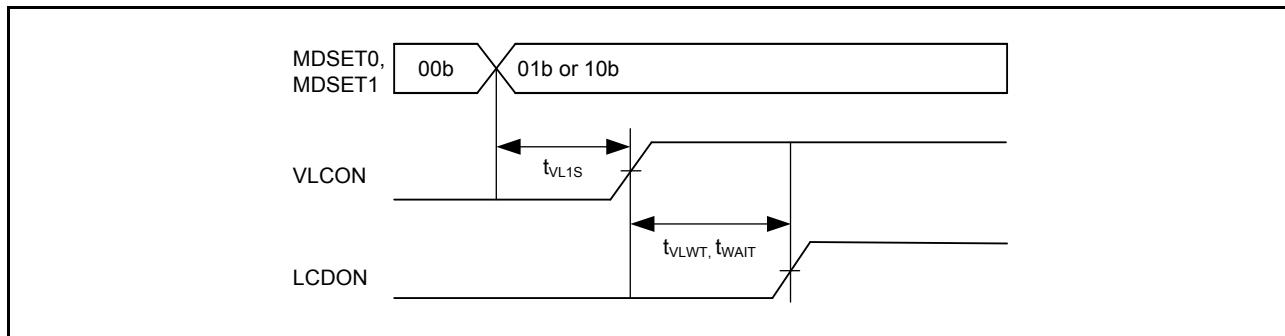


Figure 2.93 LCD reference voltage setup time, voltage boosting wait time, and capacitor split wait time

## 2.13 Comparator Characteristics

**Table 2.73 ACMPLP characteristics**

Conditions: VCC = 1.8 to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit	Test conditions	
Reference voltage range	Standard mode	IVREFn (n = 0,1)	VREF	0	-	VCC - 1.4	V	-	
	Window mode*2	IVREF1	VREFH	1.4	-	VCC	V	-	
		IVREF0	VREFL	0	-	VCC - 1.4	V	-	
Input voltage range		VI	0	-	VCC	V	-		
Internal reference voltage			-	1.36	1.44	1.50	V	-	
Output delay	High-speed mode		Td	-	-	1.2	μs	VCC = 3.0 Slew rate of input signal > 50 mV/μs	
	Low-speed mode			-	-	5	μs		
	Window mode			-	-	2	μs		
Offset voltage*1	High-speed mode		-	-	-	50	mV	-	
	Low-speed mode		-	-	-	40	mV	-	
	Window mode		-	-	-	60	mV	-	
Operation stabilization wait time			T <sub>cmp</sub>	100	-	-	μs	-	

Note 1. When 8-bit DAC output is used as the reference voltage, the offset voltage increases up to  $2.5 \times VCC/256$ .Note 2. In window mode, be sure to satisfy the following condition: IVREF1 - IVREF0  $\geq 0.2$  V.

## 2.14 OPAMP Characteristics

**Table 2.74 OPAMP characteristics (1 of 2)**

Conditions: VCC = AVCC0 = 1.8 to 5.5 V (AVCC0 = VCC when VCC &lt; 2.0 V)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Common mode input range	Vicm1	Low-power mode	0.2	-	AVCC0 - 0.5	V
	Vicm2	High-speed mode	0.3	-	AVCC0 - 0.6	V
Output voltage range	Vo1	Low-power mode	0.1	-	AVCC0 - 0.1	V
	Vo2	High-speed mode	0.1	-	AVCC0 - 0.1	V
Input offset voltage	Vioff	3σ	-10	-	10	mV
Open gain	Av		60	120	-	dB
Gain-bandwidth (GB) product	GBW1	Low-power mode	-	0.04	-	MHz
	GBW2	High-speed mode	-	1.7	-	MHz
Phase margin	PM	CL = 20 pF	50	-	-	deg
Gain margin	GM	CL = 20 pF	10	-	-	dB

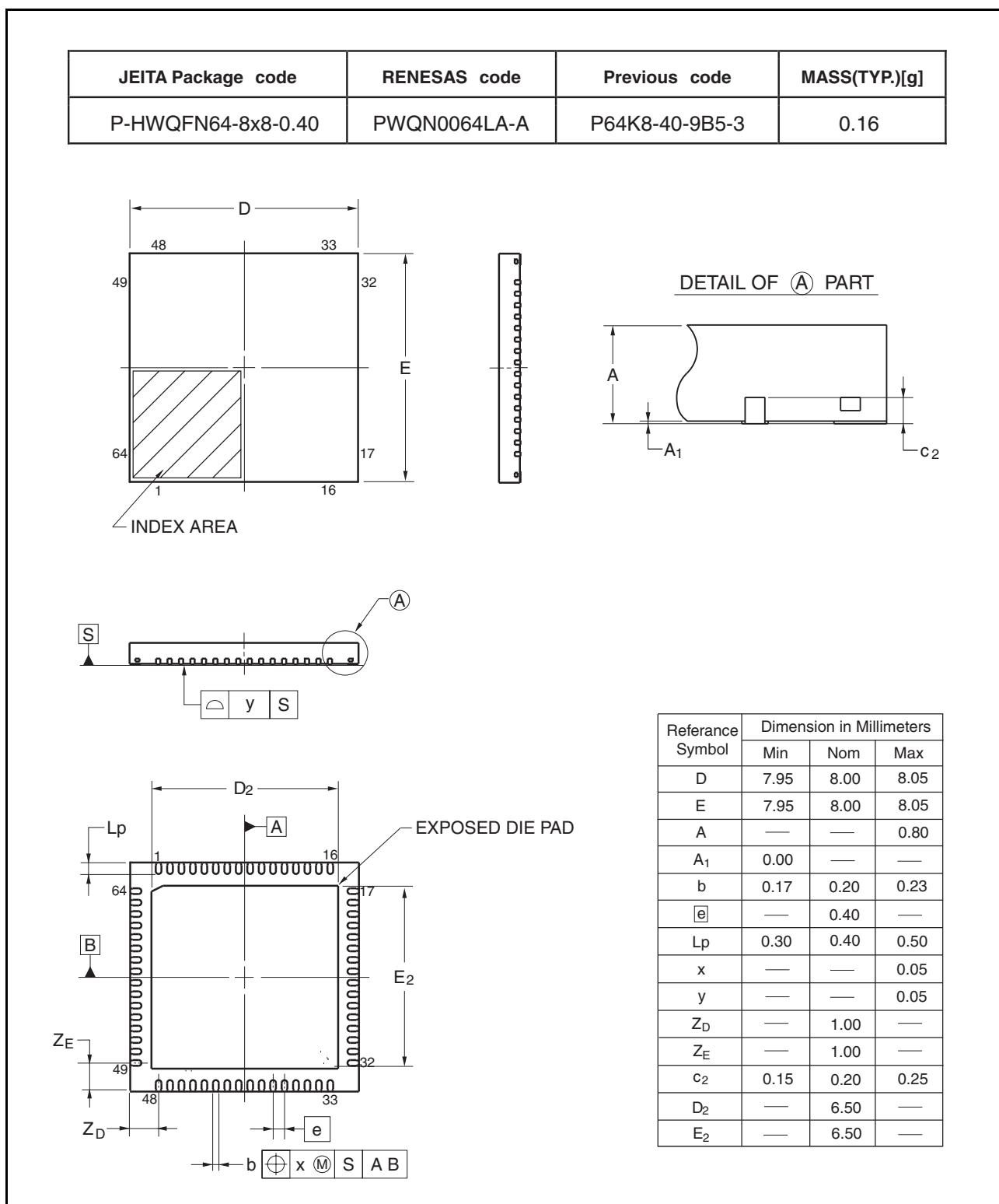


Figure 1.7 QFN 64-pin